

THURSDAY 1.9.

		08:30	Get Together
Session n°3	Talk 6	09:00	The patterning toolbox FIB-o-mat: Exploiting the full potential of focused ion beams for nanofabrication - <i>K. Höflich</i>
	Inv 2	09:25	Focused Ion Beam Induced Strain Generation in Silicon Membranes - <i>D. Cox</i>
	Exi 4	10:00	Two Microscopes are better than One – In-situ Correlative Analysis by combination of AFM, SEM, and FIB - <i>C. Schwab (Quantum Design)</i>
		10:25	COFFEE BREAK
Session n°4	Talk 7	11:00	Direct-Write 3D Nanoprinting of High-Resolution Magnetic Force Microscopy Nanoprobes - <i>M. Brugger-Hatzl</i>
	Inv 3	11:25	Armin Götzhäuser - TBA
	Exi 5	12:00	Tescan - TBA
		12:30	LUNCH + Discussions
Session n°5	Talk 8	14:00	Sample preparation and analysis of LLZO ceramics for solid state batteries with Cryo FIB/SEM and aberration corrected analytical STEM - <i>C. J. Burkhardt</i>
	Talk 9	14:25	Helium ion microscopy and sectioning of Spider Silk - <i>J. Fiutowski</i>
	Inv 4	14:50	Best Practices for Xe PFIB Preparation of Materials for Transmission Electron Microscopy - <i>S. Vitale</i>
	Exi 6	15:25	New Applications in Energy Research Enabled by a Triple Beam, Dual Chamber FIB with Isotropic Tomographic Voxels - <i>B. Tordoff (Zeiss)</i>
		15:50	TBA
		16:15	POSTER SESSION COFFEE / BEER
		18:30	Meet at Rickmer Rickmers for Conference Dinner